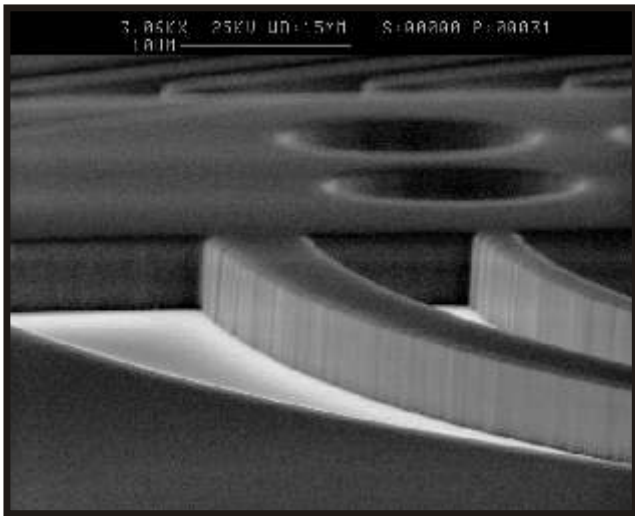
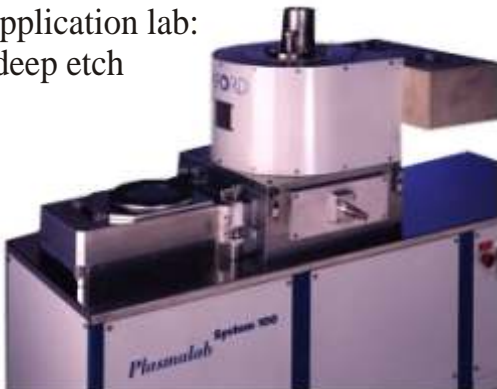


Plasmalab Data

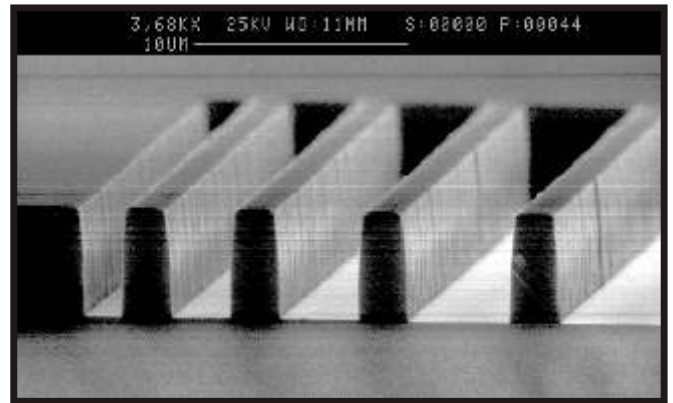
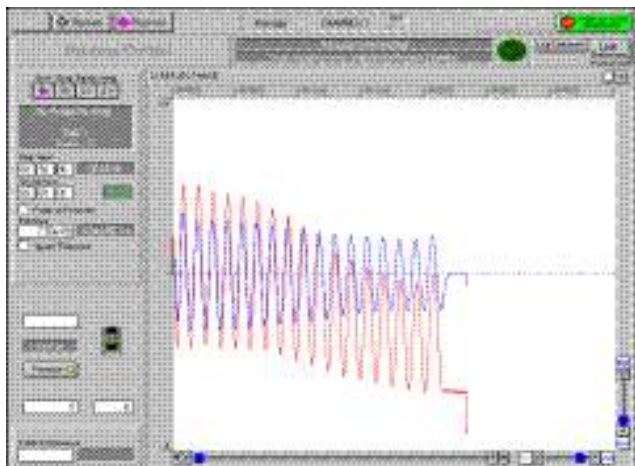
AlGaN/ GaN ICP Etching



OPT application lab:
8 μm deep etch

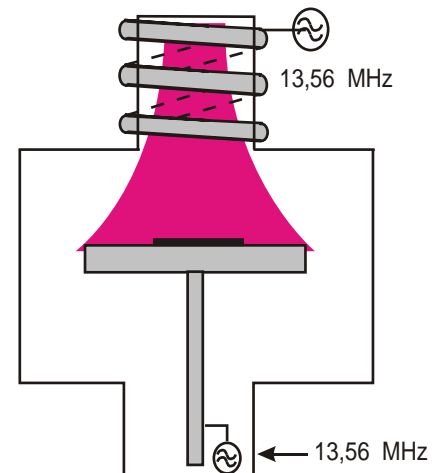


OPT application lab:
laser endpoint scan from GaN etch



OPT application lab:
10 μm deep AlGaN/ GaN etch

- Plasmalab 80 Plus*
- Plasmalab System 100*
- Plasmalab System 133*



Technology:

- Reactive Ion Etching with ICP Source (2 or 13 MHz)
- Inductive Coupled Plasma
- RF driven substrate electrode
- Cl based processes

Results:

- rate: 0.5 - 1 $\mu\text{m}/\text{min}$ with SiO_2 mask
- 0.3 $\mu\text{m}/\text{min}$ with photoresist mask
- selectivity to SiO_2 5 - 10 : 1, to PR 1.15 : 1
- anisotropic profile
- clean etch surface
- low ion induced damage